

Notice of References Cited	Application/Control No. 10/702,429	Applicant(s)/Patent Under Reexamination YASUI ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,568,177	05-2003	Surnilla, Gopichandra	60/285
	B	US-6,564,543	05-2003	Orzel et al.	60/277
	C	US-6,539,704	04-2003	Surnilla et al.	60/274
	D	US-6,370,935	04-2002	He et al.	73/1.34
	E	US-6,308,697	10-2001	Surnilla et al.	123/672
	F	US-5,758,494	06-1998	Davey, Christopher Kirk	60/274
	G	US-5,365,216	11-1994	Kotwicki et al.	340/439
	H	US-5,363,091	11-1994	Kotwicki et al.	340/439
	I	US-5,325,711	07-1994	Hamburg et al.	73/118.1
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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